



UNIVERSITY OF CENTRAL FLORIDA  
AMPAC

University of Central Florida  
Advanced Materials Processing and Analysis Center  
Materials Characterization Facility  
12443 Research Parkway, Suite 304  
(Orlando Tech Center in Research Park)  
Orlando, FL 32826 , 407-882-1500

# OPEN HOUSE

September 26, 2008, Friday, 2 pm - 4pm

## MATERIALS CHARACTERIZATION FACILITY

ADVANCED MATERIALS PROCESSING AND ANALYSIS CENTER

Materials Characterization Facility (MCF) is a user facility that provides faculty, researchers, students and industrial partners access to various surface and materials characterization equipment and capabilities.

What Do You Want to See?  
Who Do You Contact?  
What Equipment to Use?  
How To Sign-up?  
Samples of Work  
Tour of Equipment  
Snacks and Beverages

Scanning Electron Microscopes  
Transmission Electron Microscopes  
Focused Ion Beam  
Atomic Force Microscope  
X-ray Diffraction  
Electron Probe Microanalysis  
Secondary Ion Mass Spectroscopes  
X-ray Photoelectron Spectroscope  
Auger Electron Spectroscope  
Rutherford Backscatter Spectroscope  
And Many More

For more information, Please contact Karen Glidewell or Dr. Yongho Sohn  
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